

IN THE SPECIFICATION:

Please replace the second paragraph of page 13 of the Disclosure currently on file with the following paragraph:

FIG. 10 shows the relationship between the annealing temperature in an inert atmosphere and the crystal grain size. The ruthenium film is formed in accordance with Recipe 10 of FIG. 5B, and the crystal grain size of the ruthenium film is determined through the cross-section TEM observation of the ruthenium film. The size of the crystal grain (just after being formed) is about 10 nm, and the surface thereof is also coarse. However, by performing annealing at not less than the formation temperature, the size of each crystal grain increases, and the crystal grains become uniform with an average grain size of 40 nm, while ranging from 30 nm to 60 nm, at 400 °C. Further, it is also found that no change occurs at a temperature higher than 400°C (i.e. from 400 °C to 800 °C).